Search Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/041,005	HALASZ ET AL.	
Examiner	Art Unit	_
Shin-Hon Chen	2131	

-	SEARCHED			
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
USPAT, PGPUB, DERWENT, JPO, EPO (BRS search- see search history)	3/14/2007	S.C.